

## Freeform Search

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<b>Database:</b>	US Pre-Grant Publication Full-Text Database
	US Patents Full-Text Database
	US OCR Full-Text Database
	EPO Abstracts Database
	JPO Abstracts Database
	Derwent World Patents Index
	IBM Technical Disclosure Bulletins

  

<b>Term:</b>	<input type="text" value="l2 and L3"/>
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<b>Display:</b>	<input type="text" value="20"/>	<b>Documents in Display Format:</b>	<input type="text" value="-"/>	<b>Starting with Number</b>	<input type="text" value="1"/>
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**Generate:** ☐ Hit List ☒ Hit Count ☐ Side by Side ☐ Image

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Search

Clear

Interrupt

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### Search History

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**DATE:** Thursday, September 16, 2004    [Printable Copy](#)    [Create Case](#)

**Set Name Query**  
side by side

**Hit Count Set Name**  
result set

*DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=ADJ*

<u>L5</u>	L2 not l4	48	<u>L5</u>
<u>L4</u>	l2 and L3	35	<u>L4</u>
<u>L3</u>	707/\$.ccls.	22448	<u>L3</u>
<u>L2</u>	L1 and disambiguate\$	83	<u>L2</u>
<u>L1</u>	classif\$ near3 (term\$ or keyword or vocabulary or categor\$)	14279	<u>L1</u>

END OF SEARCH HISTORY

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Your search matched **0** of **1071730** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

## Refine This Search:

You may refine your search by editing the current search expression or enter a new one in the text box.

classif\$ and (term\* or keyword\* or vocabular\* or category\*)

Search

☐ Check to search within this result set

## Results Key:

JNL = Journal or Magazine CNF = Conference STD = Standard

## Results:

No documents matched your query.

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